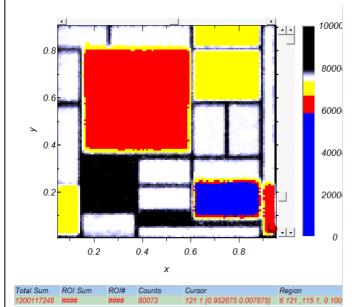
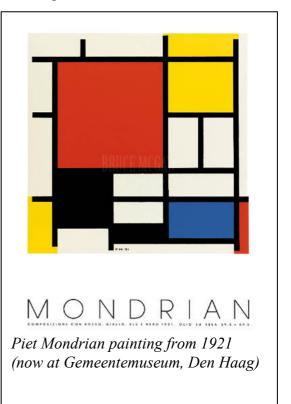
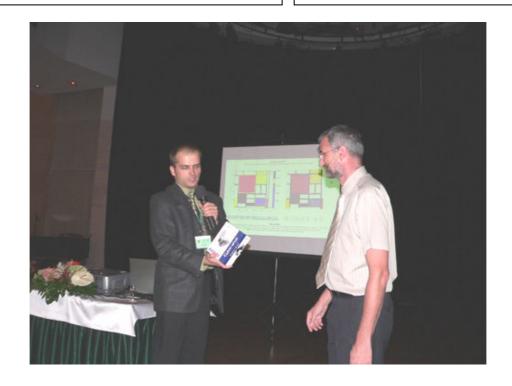
## IBIC and Mondrian

by Milko Jakšić, Željko Pastuović, Natko Skukan, Mladen Bogovac, Paolo Olivero, Ettore Vittone



Radiation damage structures induced by 7 MeV carbon ions in Si pin diode and imaged by IBIC technique using the same ions. Scan size is 400 x  $400 \text{ µm}^2$ . Charge collection efficiency decreases according to the color scale from the highest (black) to the lowest (blue).





Milko Jaksic is awarded the Zeiss prize for the best ion microbeam image submitted at the ICNMTA2008.